

Device Modeling Report

COMPONENTS:BIPOLAR JUNCTION TRANSISTOR
PART NUMBER:2SC3415S
MANUFACTURER:ROHM

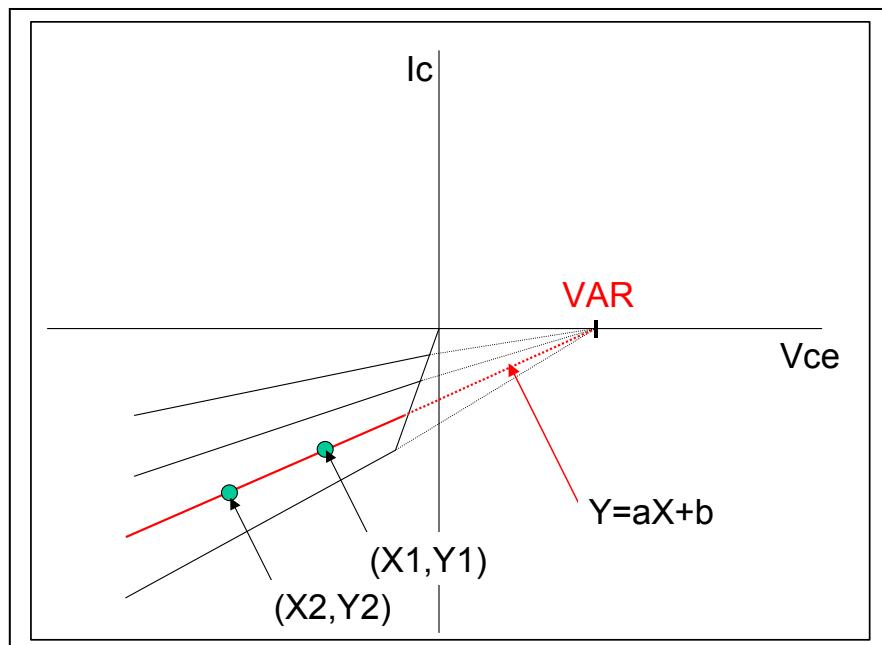
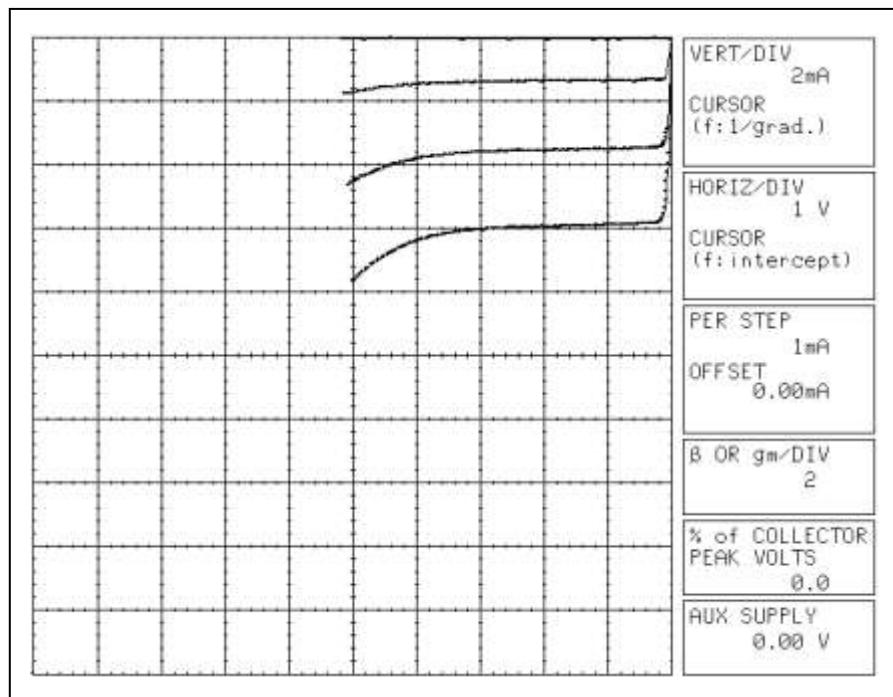


Bee Technologies Inc.

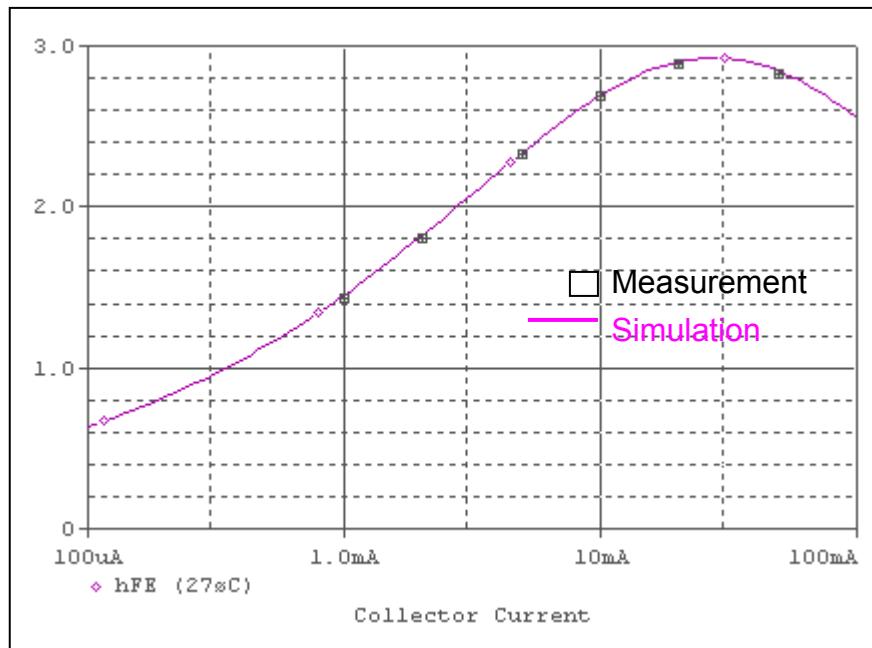
| Pspice model parameter | Model description |
|------------------------|---|
| IS | Saturation Current |
| BF | Ideal Maximum Forward Beta |
| NF | Forward Current Emission Coefficient |
| VAF | Forward Early Voltage |
| IKF | Forward Beta Roll-off Knee Current |
| ISE | Non-ideal Base-Emitter Diode Saturation Current |
| NE | Non-ideal Base-Emitter Diode Emission Coefficient |
| BR | Ideal Maximum Reverse Beta |
| NR | Reverse Emission Coefficient |
| VAR | Reverse Early Voltage |
| IKR | Reverse Beta Roll-off Knee Current |
| ISC | Non-ideal Base-Collector Diode Saturation Current |
| NC | Non-ideal Base-Collector Diode Emission Coefficient |
| NK | Forward Beta Roll-off Slope Exponent |
| RE | Emitter Resistance |
| RB | Base Resistance |
| RC | Series Collector Resistance |
| CJE | Zero-bias Emitter-Base Junction Capacitance |
| VJE | Emitter-Base Junction Potential |
| MJE | Emitter-Base Junction Grading Coefficient |
| CJC | Zero-bias Collector-Base Junction Capacitance |
| VJC | Collector-base Junction Potential |
| MJC | Collector-base Junction Grading Coefficient |
| FC | Coefficient for Onset of Forward-bias Depletion Capacitance |
| TF | Forward Transit Time |
| XTF | Coefficient for TF Dependency on Vce |
| VTF | Voltage for TF Dependency on Vce |
| ITF | Current for TF Dependency on Ic |
| PTF | Excess Phase at $f=1/2\pi*TF$ |
| TR | Reverse Transit Time |
| EG | Activation Energy |
| XTB | Forward Beta Temperature Coefficient |
| XTI | Temperature Coefficient for IS |

Reverse

Reverse Early Voltage Characteristic

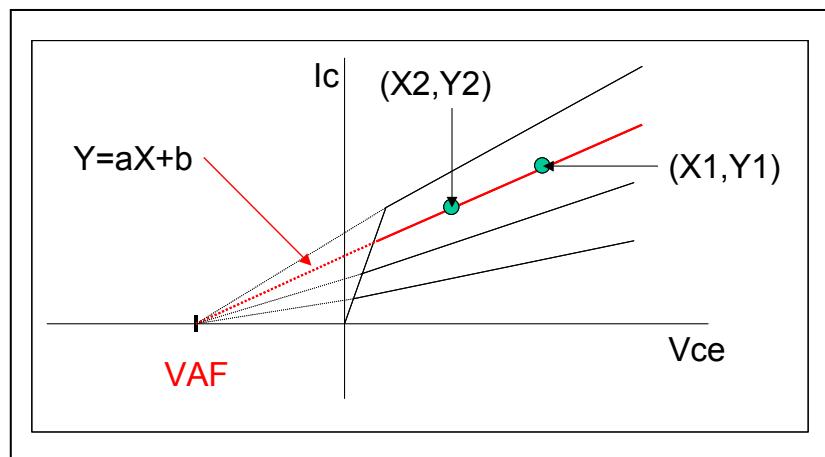
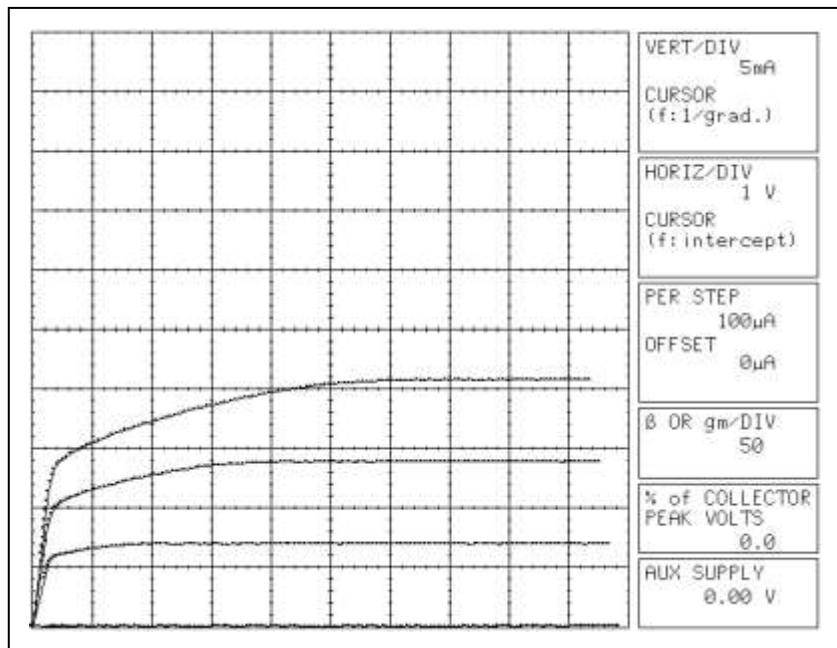


Reverse DC Beta Characteristic (I_e vs. h_{FE})

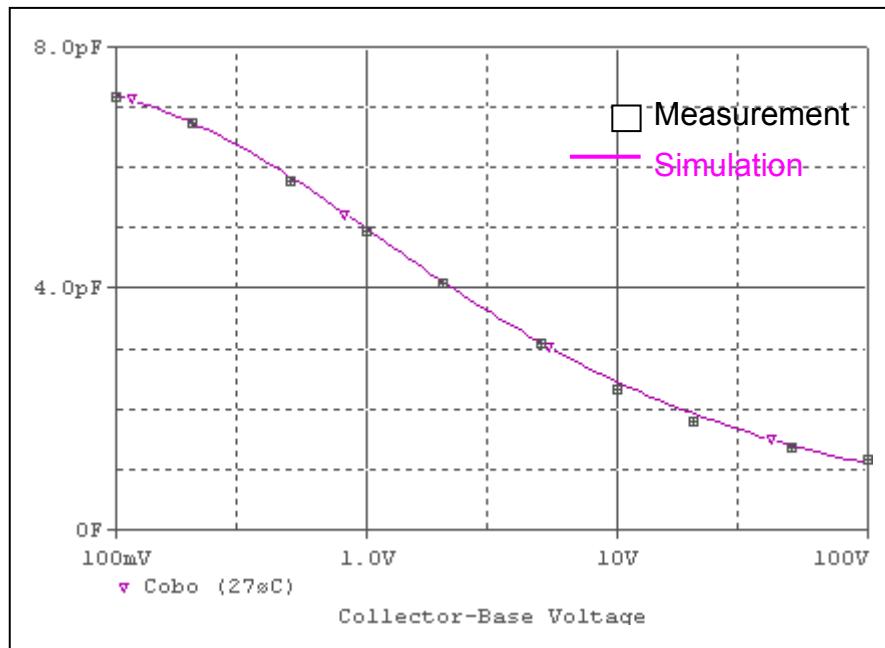


Forward

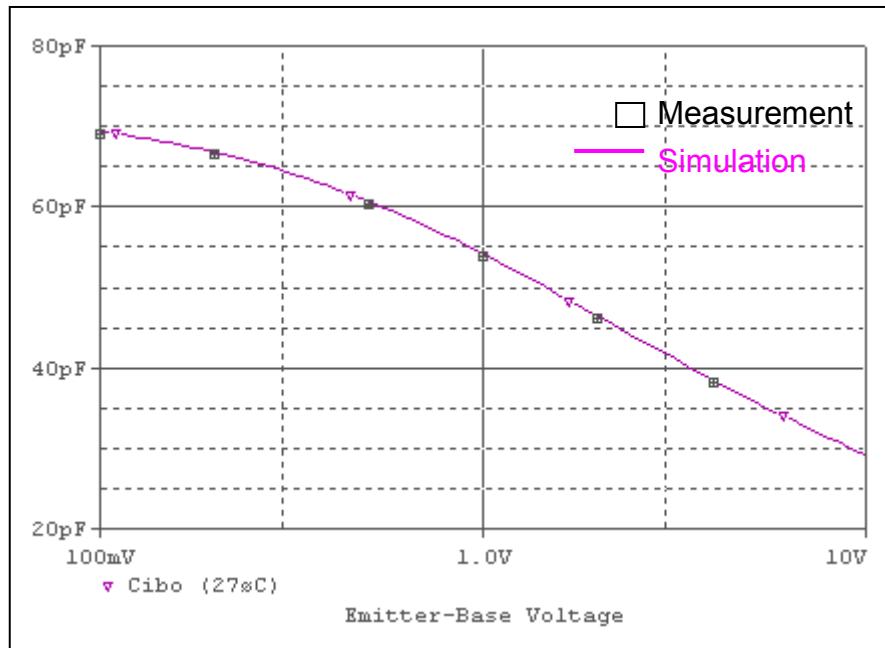
Forward Early Voltage Characteristic



C-B Capacitance Characteristic

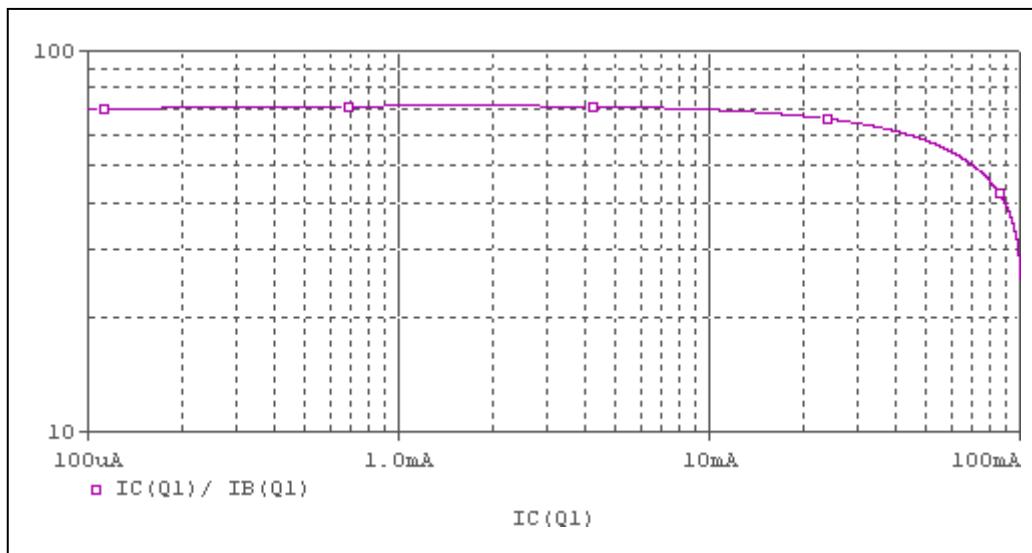


E-B Capacitance Characteristic

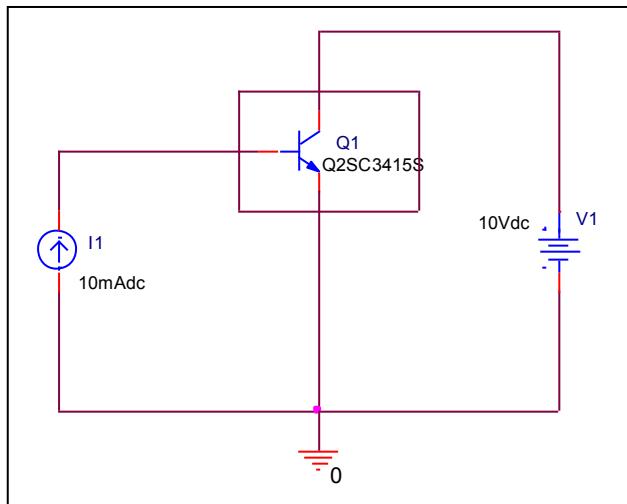


BJT Ic-hFE characteristics

Circuit simulation result

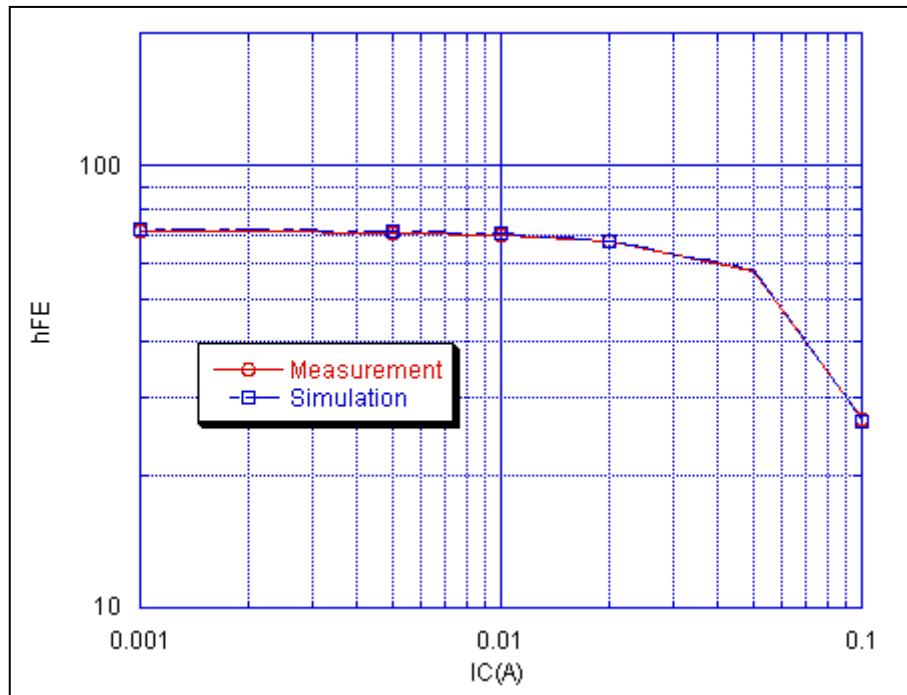


Evaluation circuit



Comparison Graph

Circuit simulation result

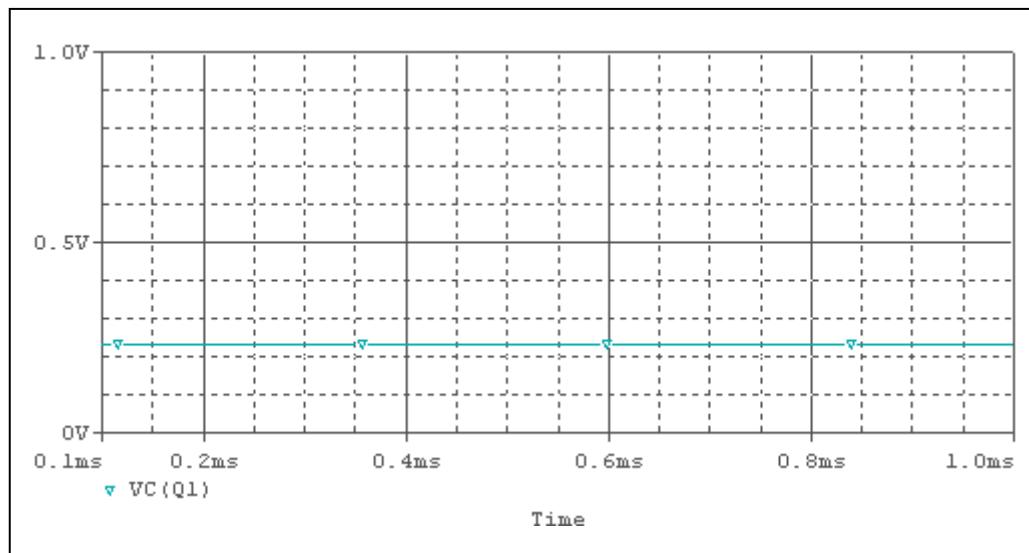


Simulation result

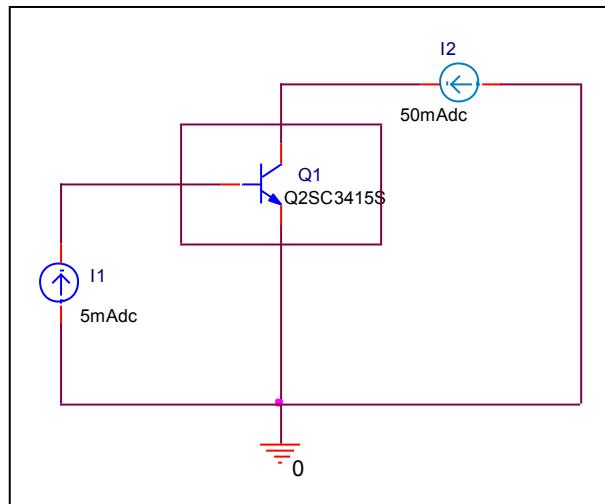
| Ic(A) | hFE | | %Error |
|-------|-------------|------------|-------------|
| | Measurement | Simulation | |
| 0.001 | 71.428 | 71.694 | 0.372402979 |
| 0.002 | 71.428 | 71.747 | 0.446603573 |
| 0.005 | 70.822 | 71.273 | 0.636807772 |
| 0.01 | 69.93 | 70.112 | 0.26026026 |
| 0.02 | 67.686 | 67.467 | 0.323552877 |
| 0.05 | 58.072 | 58.152 | 0.137760022 |
| 0.1 | 26.737 | 26.381 | 1.3314882 |

BJT Vce(sat) voltage Characteristics

Circuit simulation result



Evaluation circuit



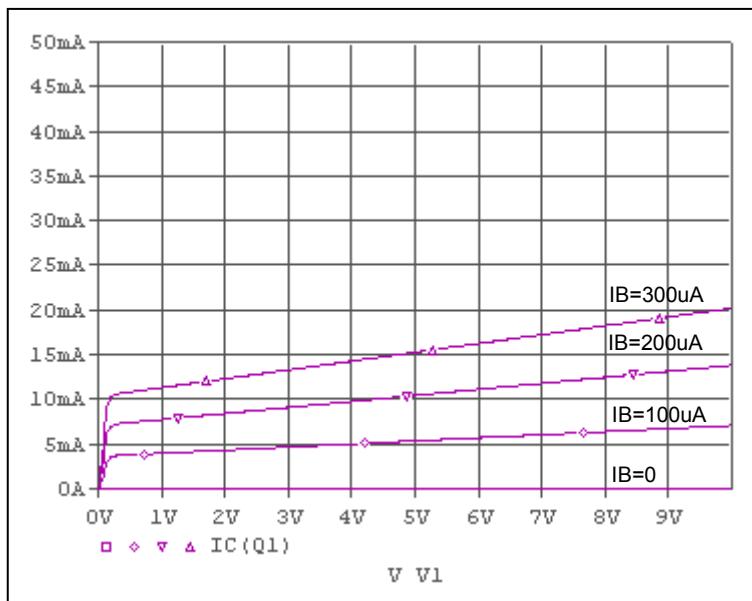
Simulation result

Test condition: IC/IB = 10, IC=50mA

| Vce(sat)(V) | | |
|-------------|------------|----------|
| Measurement | Simulation | Error(%) |
| 2[Max] | 0.229 | - |

Output Characteristics

Circuit simulation result



Evaluation circuit

